



N-Channel Enhancement Mode Field Effect Transistor

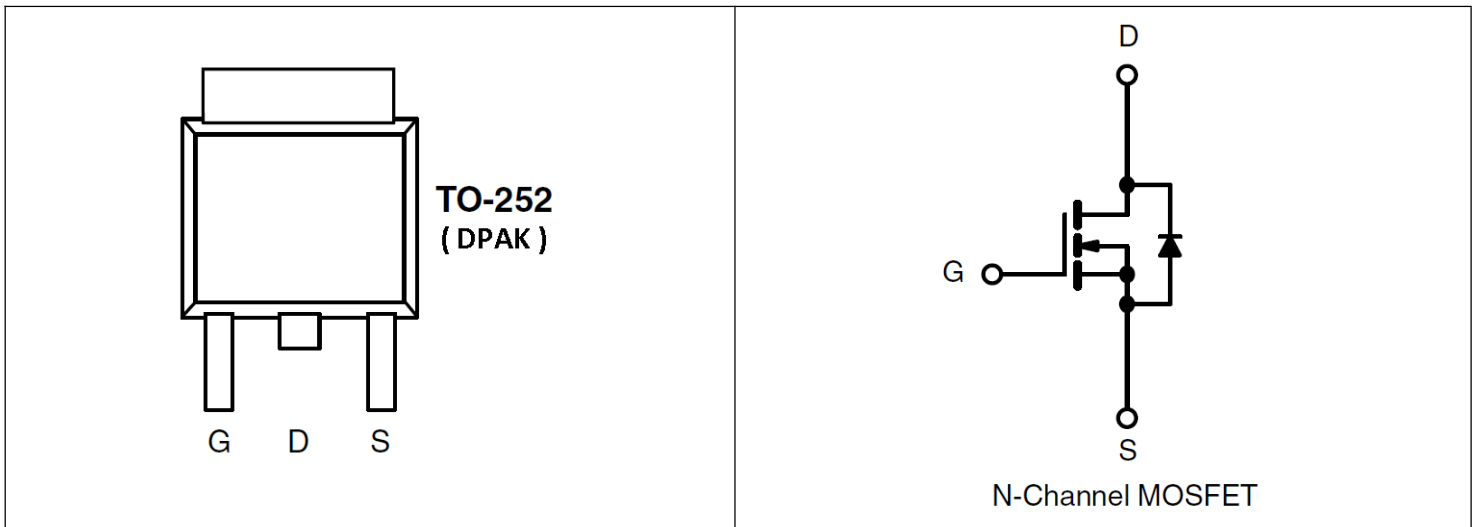


Features:

- $V_{DS}=30V$
- $I_D=60A(T_c=25^\circ C, V_{GS}=10V)$
- $R_{DS(ON)} \leq 6.5m\Omega @V_{GS}=10V$
- $R_{DS(ON)} \leq 10m\Omega @V_{GS}=4.5V$
- High Density Cell Design for Ultra Low On-Resistance.
- Lead free product is acquired.

Applications:

- Switching Applications.



Absolute Maximum Ratings ($T_A = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	Ratings	Units
V_{DS}	Drain-Source Voltage	30	V
V_{GS}	Gate-Source Voltage	20	V
I_D	Continuous Drain Current <small>$T_c=25^\circ C$</small>	60	A
I_{DM}	Pulsed Drain Current ²	160	A
I_S	Continuous Source Current (Diode Conduction) ¹	40	A
P_D	Maximum Power Dissipation ¹ <small>$T_c=25^\circ C$</small>	50	W
T_J, T_{stg}	Operating Junction and Storage Temperature Range	-55 to 150	$^\circ C$

Thermal Resistance Ratings

Symbol	Parameter	Ratings	Unit
R_{thJA}	Maximum Junction-to-Ambient	52	$^\circ C/W$

Notes:

1. Surface Mounted on 1" x 1" FR4 Board, $t \leq 10$ Sec.



2. Pulse width limited by maximum junction temperature.

Electrical Characteristics ($T_A=25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Test Condition	Min	Typ	Max	Unit
● Static Characteristics						
B_{VDSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_{DS}=250\mu A$	30	-	-	V
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	1.0	1.6	2.0	V
I_{GSS}	Gate-Body Leakage Current	$V_{DS}=0V, V_{GS}=\pm 20V$	-	-	± 100	nA
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=24V, V_{GS}=0V$	-	-	1	μA
		$V_{DS}=24V, V_{GS}=0V, T_J=85^\circ\text{C}$	-	-	30	
$R_{DS(on)}$	Drain Source On State Resistance ^a	$V_{GS}=10V, I_D=25A$	-	5	6.5	m Ω
		$V_{GS}=4.5V, I_D=20A$	-	7.5	10	
V_{SD}	Diode Forward Voltage ^a	$I_S=25A, V_{GS}=0V$	-	0.7	1.3	V
● Dynamic Characteristics ^b						
C_{iss}	Input Capacitance	$V_{DS}=15V, V_{GS}=0V, f=1\text{MHz}$	-	2200	-	pF
C_{oss}	Output Capacitance					
C_{riss}	Reverse Transfer Capacitance					
Q_g	Total Gate Charge	$V_{DS}=15V, V_{GS}=10V, I_D=25A$	-	37	-	nC
Q_{gs}	Gate-Source Charge					
Q_{gd}	Gate-Drain Charge					
$t_{d(on)}$	Turn-On Delay Time	$V_{DS}=15V, V_{GS}=10V$ $I_D=20A, R_G=4.7\Omega$	-	10	-	nSec
t_r	Rise Time					
$T_{d(off)}$	Turn-Off Delay Time					
t_f	Fall Time					
R_g	Gate Resistance	$V_{DS}=0V, V_{GS}=0V, f=1\text{MHz}$	-	1.9	-	Ω
t_{rr}	Source-Drain Reverse Recovery Time	$I_S=25A, di/dt=100A/\mu s$	-	32	-	nSec

Note:

a. Pulse test; pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$.

b. Guaranteed by design, not subject to production testing.



Typical Characteristics (Tc=25°C unless otherwise noted)

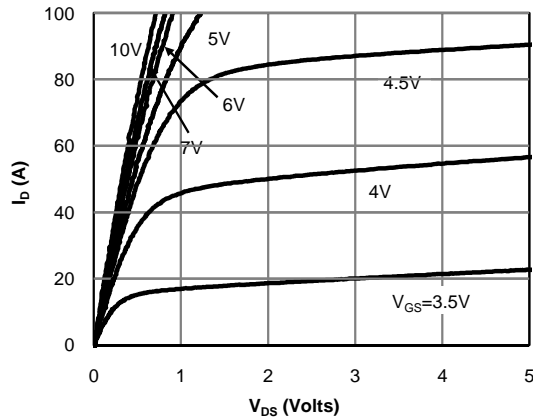


Figure 1: On-Region Characteristics (Note E)

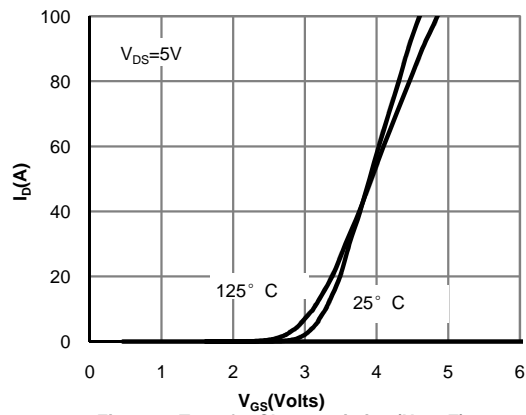


Figure 2: Transfer Characteristics (Note E)

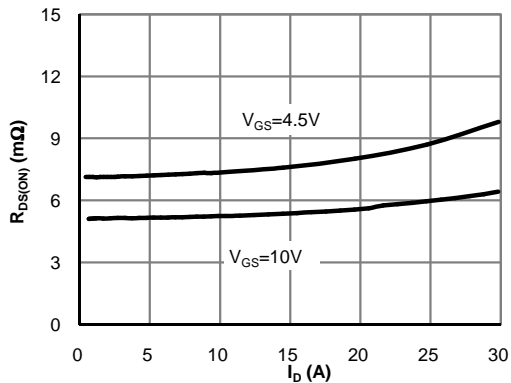


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

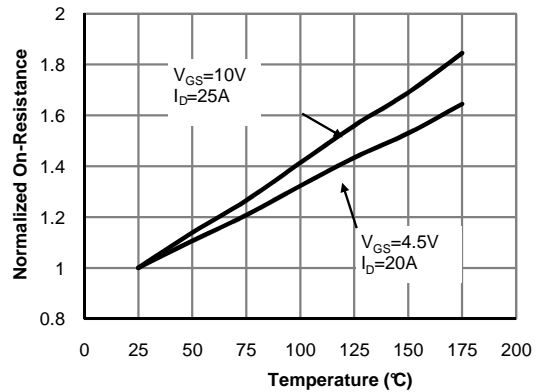


Figure 4: On-Resistance vs. Junction Temperature (Note E)

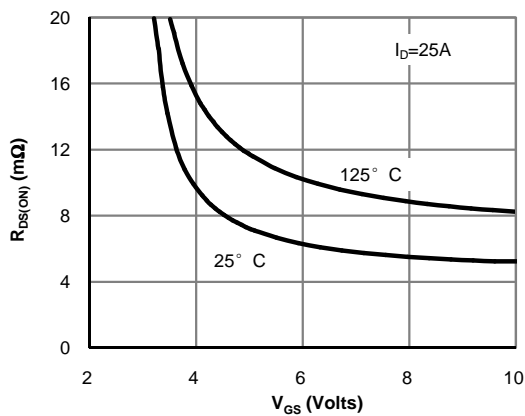


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

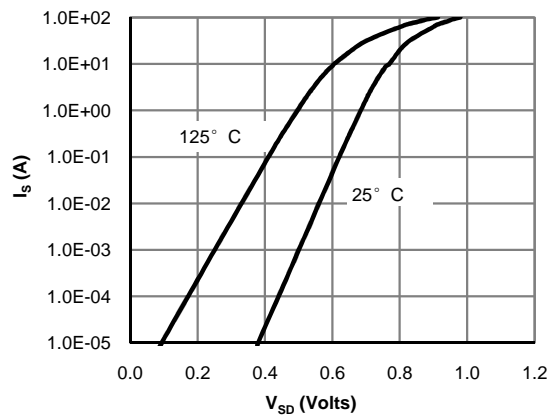


Figure 6: Body-Diode Characteristics (Note E)



Typical Characteristics (Tc=25°C unless otherwise noted)

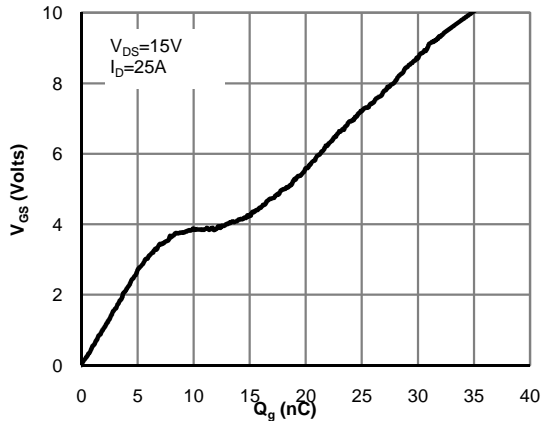


Figure 7: Gate-Charge Characteristics

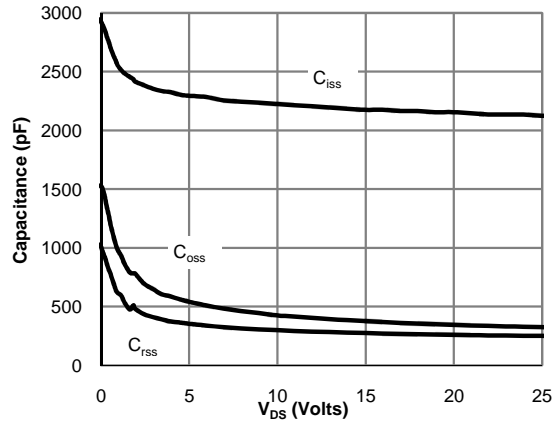


Figure 8: Capacitance Characteristics

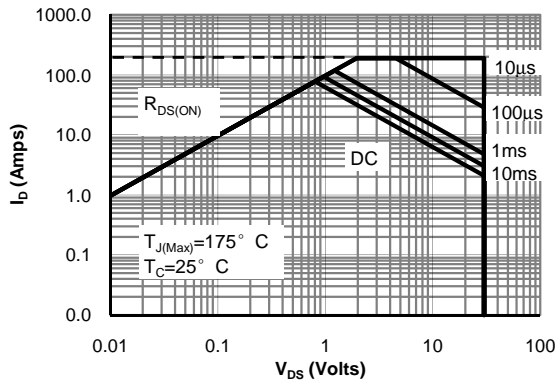


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

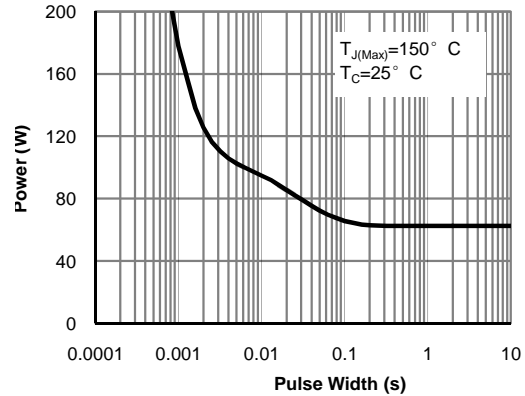


Figure 10: Single Pulse Power Rating Junction-to-

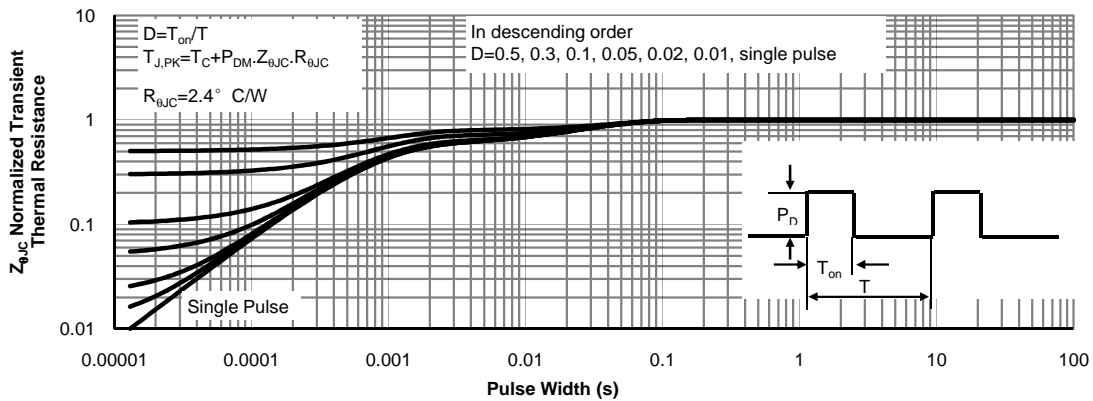


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)



Typical Characteristics (Tc=25°C unless otherwise noted)

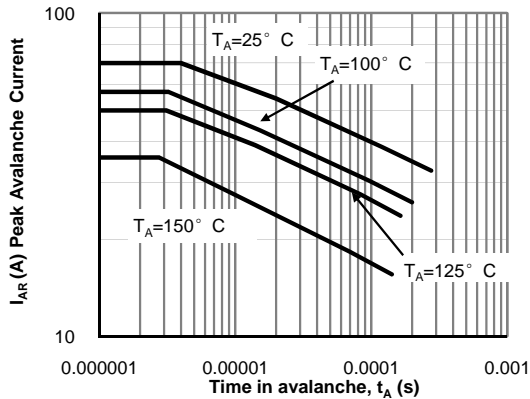


Figure 12: Single Pulse Avalanche capability (Note C)

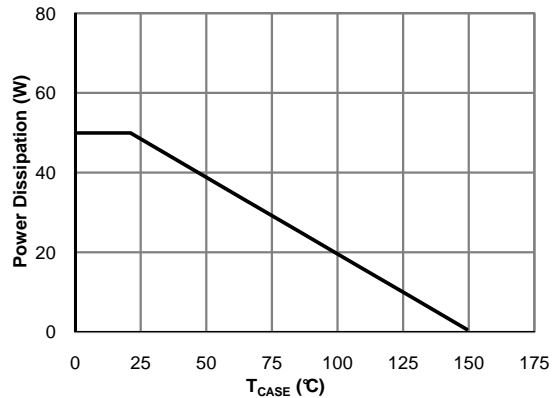


Figure 13: Power De-rating (Note F)

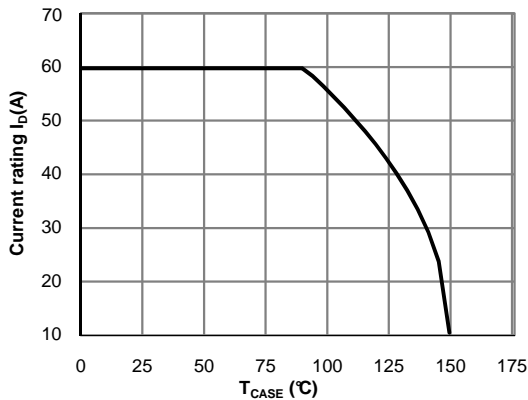


Figure 14: Current De-rating (Note F)

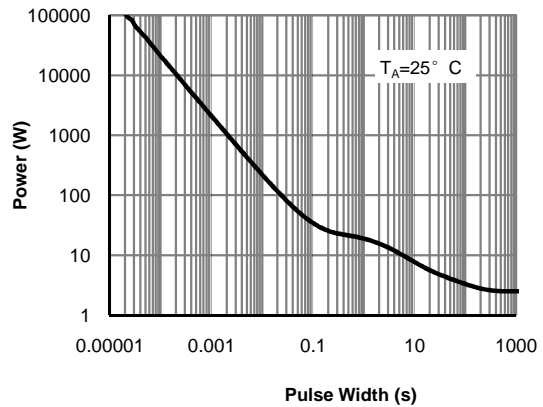


Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note H)

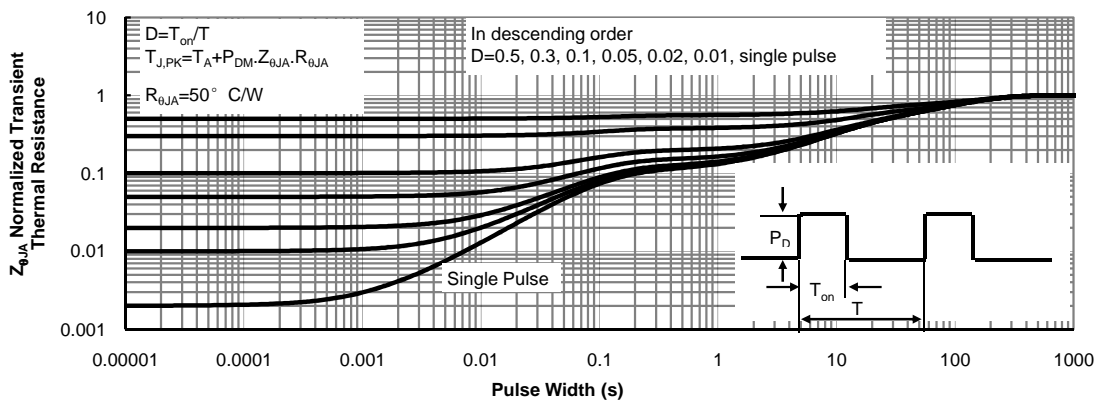
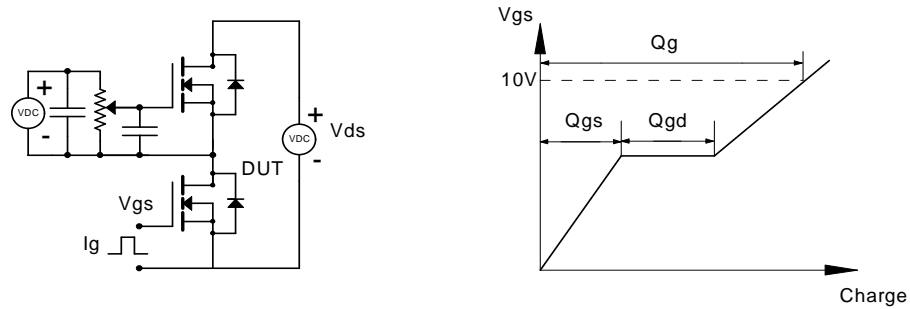


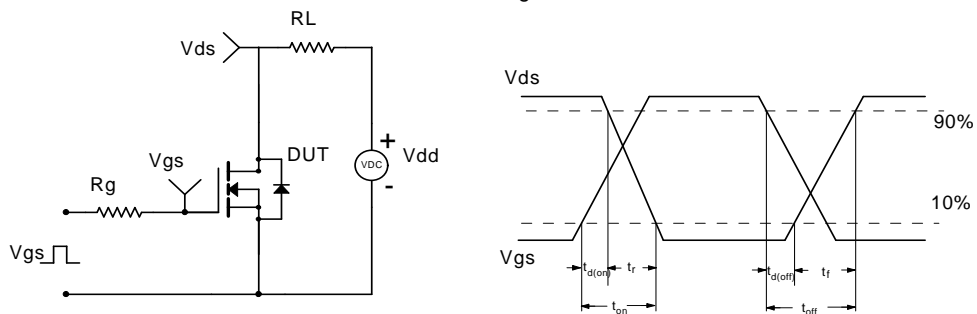
Figure 16: Normalized Maximum Transient Thermal Impedance (Note H)



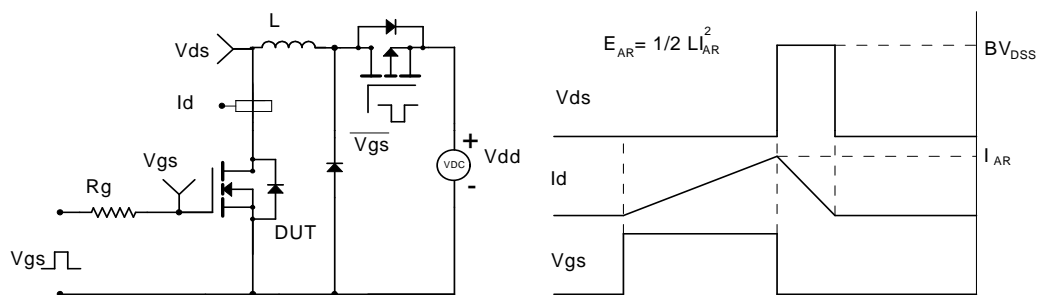
Gate Charge Test Circuit & Waveform



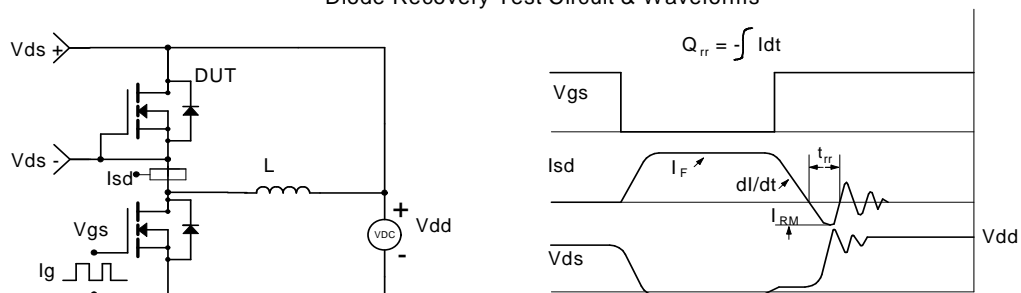
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



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